PL 7-07-05

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

267

In re the Application of

asoshi INOUE et al.

cation No.: 09/899,058

July 6, 2001

SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURE

Docket No.: 11

ocket No.. 114

RECEIVE

JUN 2 7 2002

Director of the U.S. Patent and Trademark Office Washington, D.C. 20231

Technology Center 2600

Sir:

For:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

INFORMATION DISCLOSURE STATEMENT

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. The references were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully submitted,

James A. Oliff

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JAO:TJP/al

Date: June 26, 2002

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE
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Form PTO-1449 (REV. 8-83)			ATTY DOCKET NO. 110041			APPLICATION NO. 09/899,058			
DIFORMATION DISCLOSURE STATEMENT									
JUN 2 6 2002 2			APPLICANTS Satoshi INOUE et al.						
U.S. PATE			FILING DATE July 6, 2001						
TRADE	U.S.	PATE	NT DOCU	JMENTS					
EXAMINER INITIAL	DOCUMENT NUMBER	D	DATE NAM		E	CLASS	SUB CLASS		
 	5,936,291	08/1	0/1999	Makita et al.					
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	FOREIC	SN PA	TENT DO	CUMENTS					
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	EP 0 166 208 A2	01/02	2/1986	Europe					
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	OTHER DOCUMENTS (Inc	cluding	Author,	Title, Date, Pertinent Page	s, etc.)				
									
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EXAMINER					DATE CONSI	DERED			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

Date: June 26, 2002